

AMENDMENTS TO THE CLAIMS

(IN FORMAT COMPLIANT WITH THE REVISED 37 CFR 1.121)

Please cancel claim 9 without prejudice.

1. (CURRENTLY AMENDED) An apparatus comprising:

a low speed tester; and

a host emulator having (i) a first interface coupled to said low speed tester to receive a test vector at a first speed,
5 (ii) a second interface configured to (a) transmit ~~said test vector~~
a first test packet to a device at a second speed faster than said first speed and (b) receive a response from said device and (iii) a third interface to said low speed tester to transfer a first done signal based upon said response, wherein said apparatus is
10 configured to allow said low speed tester to perform high speed tests of said device at said second speed.

2. (PREVIOUSLY PRESENTED) The apparatus according to claim 1, wherein said host emulator is further configured to perform a verification of said device.

3. (ORIGINAL) The apparatus according to claim 1, wherein said device comprises a Universal Serial Bus (USB) device.

4. (PREVIOUSLY PRESENTED) The apparatus according to claim 1, further comprising:

a test vector generator configured to transfer said test vector to said low speed tester.

5. (ORIGINAL) The apparatus according to claim 4, wherein said low speed tester is configured to control said host emulator.

6. (PREVIOUSLY PRESENTED) The apparatus according to claim 4, wherein said low speed tester is configured in response to said test vector.

7. (PREVIOUSLY PRESENTED) The apparatus according to claim 6, wherein said test vector generator is configured to generate said test vector.

8. (ORIGINAL) The apparatus according to claim 1, wherein said apparatus is further configured to test a reception and transmission operation of said device.

9. (CANCELED)

10. (CURRENTLY AMENDED) The apparatus according to claim 9~~1~~, wherein said device is further configured to receive and verify said first test packet ~~one or more test packets~~.

11. (CURRENTLY AMENDED) The apparatus according to claim 1, wherein said device is further configured to initiate transmission of one or more second test packets under control of said host emulator.

12. (CURRENTLY AMENDED) The apparatus according to claim 11, wherein said host emulator is further configured to receive and verify said one or more second test packets.

13. (PREVIOUSLY PRESENTED) The apparatus according to claim 1, wherein said low speed tester is further configured to (i) make a decision for a pass/fail condition of said device based on said response and (ii) generate a pass/fail signal indicating said decision.

14. (ORIGINAL) The apparatus according to claim 1, wherein said apparatus is configured to perform at least one test of a plurality of test modes wherein said plurality of test modes comprise USB 2.0 defined test modes for use in a production test environment.

15. (CURRENTLY AMENDED) An apparatus comprising:

means for transferring a test vector at a first speed to
a first interface;

means for transmitting ~~said test vector~~ a test packet
5 from a second interface to a device at a second speed faster than
said first speed;

means for receiving a response from said device at said
second interface; and

means for transferring a signal based upon said response
10 from a third interface to perform high speed tests of said device
at said second speed.

16. (CURRENTLY AMENDED) A method for testing comprising
the steps of:

(A) transferring a test vector at a first speed from a
low speed tester to a first interface of a host emulator;

5 (B) transmitting ~~said test vector~~ a first test packet
from a second interface of said host emulator at a second speed
faster than said first speed to a device;

(C) receiving a response from said device at said second
interface; and

10 (D) transferring a first done signal from a third
interface of said host emulator to said low speed tester based upon
said response to perform high speed tests of said device at said
second speed.

17. (PREVIOUSLY PRESENTED) The method according to claim 16, wherein said device comprises a USB device.

18. (PREVIOUSLY PRESENTED) The method according to claim 16, further comprising the step of:

configuring said low speed tester to control said host emulator.

19. (PREVIOUSLY PRESENTED) The method according to claim 18, further comprising the step of:

generating said test vector external to said low speed tester.

20. (ORIGINAL) The method according to claim 16, further comprising performing at least one of a plurality of test modes wherein the plurality of test modes comprise USB 2.0 defined test modes for use in a production test environment.

21. (CURRENTLY AMENDED) The apparatus according to claim 1, wherein said host emulator is configured to generate said first done signal to indicate one of (i) successful reception of a second test packet initiated from said device within a predetermined time and (ii) no successful reception of said second test packet within said predetermined time.

22. (CURRENTLY AMENDED) The apparatus according to claim 1, wherein said device is configured to assert a second done signal through a discrete output in response to successfully receiving said first test packet ~~test vector~~ from said host emulator.

23. (CURRENTLY AMENDED) The method according to claim 16, wherein said first done signal indicates one of (i) successful reception of a second test packet initiated from said device within a predetermined time and (ii) no successful reception of said second test packet within said predetermined time.

24. (CURRENTLY AMENDED) The method according to claim 16, further comprising the step of:

asserting a second done signal through a discrete output of said device in response to successfully receiving said first test packet ~~test vector~~ from said host emulator.

25. (CURRENTLY AMENDED) The method according to claim 16, further comprising the step of:

initiating transmission of one or more second test packets from said device under control of said host emulator.

26. (CURRENTLY AMENDED) The method according to claim 16, further comprising the steps of:

~~make~~ making a decision for a pass/fail condition of said device in said low speed tester based on said response; and

5 generating a pass/fail signal from said low speed tester
indicating said decision.